PHASICS
the phase control company

SID4-UHR

WAVE FRONT SENSOR

SID4-UHR Ultra-High-Resolution wavefront sensor is adapted for optics metrology needs. It combines the SID4 ease of implementation with high sampling and resolution. Its large aperture allows to get a live wavefront measurement over the complete sample under test. The SID4-UHR is optimized for **surface inspection** (roughness, high frequency defects detection...) and **optical components characterization** (lens, objective, aspherical and freeform optics...).

Built with a high-performance camera it provides incredible precision for laser characterization. The 512 x 512 (option 666 x 666) phase map sampling with such compactness make the SID4-UHR a unique tool for optics and laser metrology in both research and industry fields.

KEY FEATURES

- High Resolution 666 x 666
- High Dynamic range
- Large analysis pupil
- Instantaneous measure on large Field
- Optimal signal to noise ratio
- Compactness for easy implementation

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APPLICATIONS

1. Large aperture laser characterization
2. Optical components characterization
3. Surfaces inspection

SPECIFICATIONS

Wavelength range	400 - 1100 nm
Aperture dimension	15 x 15 mm²
Spatial resolution	29.6 µm (option 22.2 µm)
Phase and intensity Sampling	512 x 512 (option 666 x 666)
Accuracy (Absolute mode)	15 nm RMS
Phase resolution	2 nm RMS
Frame rate	8 fps
Real-time processing frequency (1)	1 Hz (full resolution)
Interface	Giga Ethernet
Dimensions (W X H X L)	60 x 60 x 70 mm
Weight	~ 450 g

(1) Using the computer provided by PHASICS on SID4 Software

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